

MALAYSIAN STANDARD

MS 61000-4-11:2015

Electromagnetic compatibility (EMC) -Part 4-11: Testing and measurement techniques - Voltage dips, short interruptions and voltage variations immunity tests (Second revision) (IEC 61000-4-11:2004, MOD)

ICS: 33.100.20

Descriptors: electromagnetic compatibility, testing, measurement, voltage dips, short interruptions, voltage variations immunity tests

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Committee representation

Association of Consulting Engineers Malaysia

The Industry Standards Committee on Generation, Transmission and Distribution of Energy (ISC E) under whose authority this Malaysian Standard was adopted, comprises representatives from the following organisations:

Atomic Energy Licensing Board Department of Standards Malaysia Federation of Malaysian Manufacturers Jabatan Kerja Raya Malaysia Malaysian Cable Manufacturers Association
Malaysian Electrical Appliances and Distributors Association Malaysian Green Technology Corporation Ministry of Domestic Trade, Co-operatives and Consumerism Ministry of International Trade and Industry Persatuan Kontraktor Elektrikal dan Mekanikal Melayu Malaysia SIRIM Berhad (Secretariat) SIRIM QAS International Sdn Bhd Suruhanjaya Komunikasi dan Multimedia Malaysia Suruhanjaya Tenaga Tenaga Nasional Berhad The Electrical and Electronics Association of Malaysia The Institution of Engineers, Malaysia Universiti Malaya Universiti Teknologi Malaysia

The Technical Committee on Power Quality which recommended the adoption of the IEC Standard as Malaysian Standard consists of representatives from the following organisations:

Association of Consulting Engineers Malaysia

Federation of Malaysian Manufacturers

Jabatan Kerja Raya Malaysia

Petroliam Nasional Berhad

Sarawak Electrical Inspectorate Unit

SIRIM Berhad (Secretariat)

SIRIM QAS International Sdn Bhd

Suruhanjaya Tenaga

Syarikat SESCO Berhad

Tenaga Nasional Berhad (Distribution Division)

The Electrical and Electronics Association of Malaysia

The Institution of Engineers, Malaysia

TNB Research Sdn Bhd

Universiti Teknologi Malaysia (Centre of Electrical Energy Systems)

Universiti Teknologi MARA

National foreword

The adoption of the IEC Standard as a Malaysian Standard was recommended by the Technical Committee on Power Quality under the authority of the Industry Standards Committee on Generation, Transmission and Distribution of Energy.

This Malaysian Standard is a modified adoption of IEC 61000-4-11:2004, *Electromagnetic compatibility (EMC) - Part 4-11: Testing and measurement techniques - Voltage dips, short interruptions and voltage variations immunity tests*, published by the International Electrotechnical Commission (IEC) with the following modifications:

- a) in the source text, "this International Standard" should read "this Malaysian Standard";
- b) the comma which is used as a decimal sign (if any), to read as a point;
- c) the basis IEC 61000-4-11 is printed in English and French versions. However, only the English version is retained for this Malaysian Standard;

d) Clause/Subclause Modifications Table 1 Preferred test level and durations for voltage dips Replace with new Table 1 where inclusion of new Class 4, as below:

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Classa	Test level and durations for voltage dips (t _s) (50Hz/60Hz)							
Class 1	Class 1 Case-by-case according to the equipment requirements							
Class 2	0 % during 1/2 cycle	0 % during 1 cycle	70 % during 25/30 ^c cycles					
Class 3	0 % during 1/2 cycle	0 % during 1 cycle	40 % during 10/12° cycles	70 % during 25/30° cycles	80 % during 250/300° cycles			
Class 4 ^d	0 % during 1/2 cycle	0 % during 1 cycle	50 % during 10/12° cycles	70 % during 25/30° cycles	80 % during 250/300° cycles			
Class X ^b	Х	Х	Х	Х	Х			

^a Classes per IEC 61000-2-4; see Annex B.

Explanation: Inclusion of new Class 4 test level is proposed for testing against voltage dip, voltage variation and short interruption compliance, where the voltage level is between 20 ms and 200 ms.

^b To be identified by product committee. For equipment connected directly or indirectly to the public network, the levels must not be less severe than Class 2.

[&]quot;25/30 cycles" means "25 cycles for 50 Hz test" and "30 cycles for 60 Hz test".
"250/300 cycles" means "250 cycles for 50 Hz test" and "300 cycles for 60 Hz test".

d Class 4 is as explained in the National foreword.

National foreword (continued)

e) reference to International Standards should be replaced by corresponding Malaysian Standards as follows:

Referenced International Standards

IEC 61000-2-8, Electromagnetic compatibility (EMC) - Part 2-8: Environment - Voltage dips and short interruptions on public electric power supply systems with statistical measurement results

IEC 61000-4-14, Electromagnetic compatibility (EMC) - Part 4-14: Testing and measurement techniques - Voltage fluctuation immunity test

Corresponding Malaysian Standards

MS IEC 61000-2-8, Electromagnetic compatibility (EMC) - Part 2-8: Environment - Voltage dips and short interruptions on public electric power supply systems with statistical measurement results

MS IEC 61000-4-14, Electromagnetic compatibility (EMC) - Part 4-14: Testing and measurement techniques - Voltage fluctuation immunity test

This Malaysian Standard cancels and replaces MS IEC 61000-4-11:2005, *Electromagnetic compatibility (EMC) - Part 4-11: Testing and measurement methods - Voltage dips, short interruptions and voltage variations immunity tests (First revision).*

Compliance with a Malaysian Standard does not of itself confer immunity from legal obligations.

NOTE. MOD on the front cover indicates a modified standard i.e. a standard adapted from an International Standard with permitted technical deviations, which are clearly identified and explained. The changes in structure are permitted provided that the altered structure permits easy comparison of the content of the two standards. Modified standards also include the changes permitted under identical correspondence.

INTERNATIONAL ELECTROTECHNICAL COMMISSION

ELECTROMAGNETIC COMPATIBILITY (EMC) -

Part 4-11: Testing and measurement techniques – Voltage dips, short interruptions and voltage variations immunity tests

FOREWORD

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International Standard IEC 61000-4-11 has been prepared by subcommittee 77A: Low frequency phenomena, of IEC technical committee 77: Electromagnetic compatibility.

This second edition cancels and replaces the first edition published in 1994 and its amendment 1 (2000). This second edition constitutes a technical revision in which

- 1) preferred test values and durations have been added for the different environment classes;
- 2) the tests for the three-phase systems have been specified.

It forms part 4-11 of IEC 61000. It has the status of a Basic EMC Publication in accordance with IEC Guide 107.

The text of this standard is based on the following documents:

FDIS	Report on voting
77A/452/FDIS	77A/455/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

The committee has decided that the contents of this publication will remain unchanged until 2008. At this date, the publication will be

- · reconfirmed;
- · withdrawn;
- · replaced by a revised edition, or
- · amended.

The contents of the interpretation sheet 1 of August 2010 have been included in this copy.